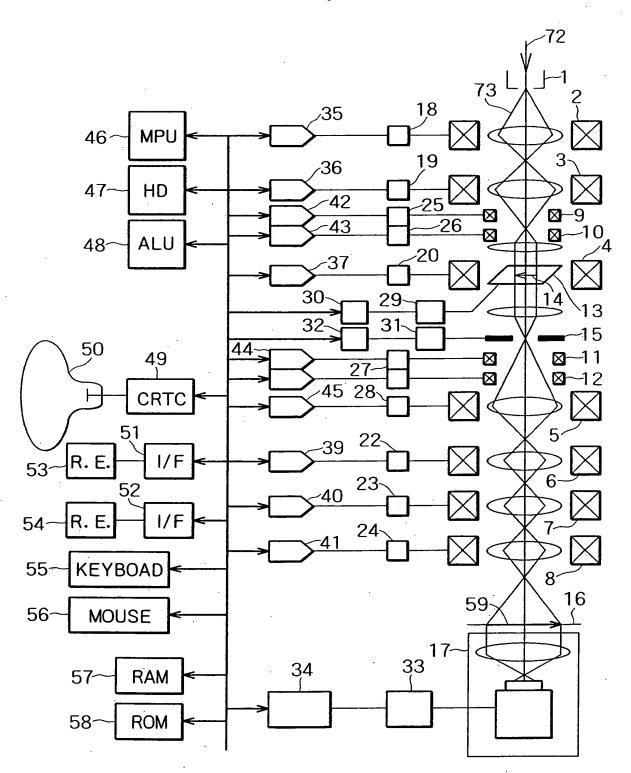
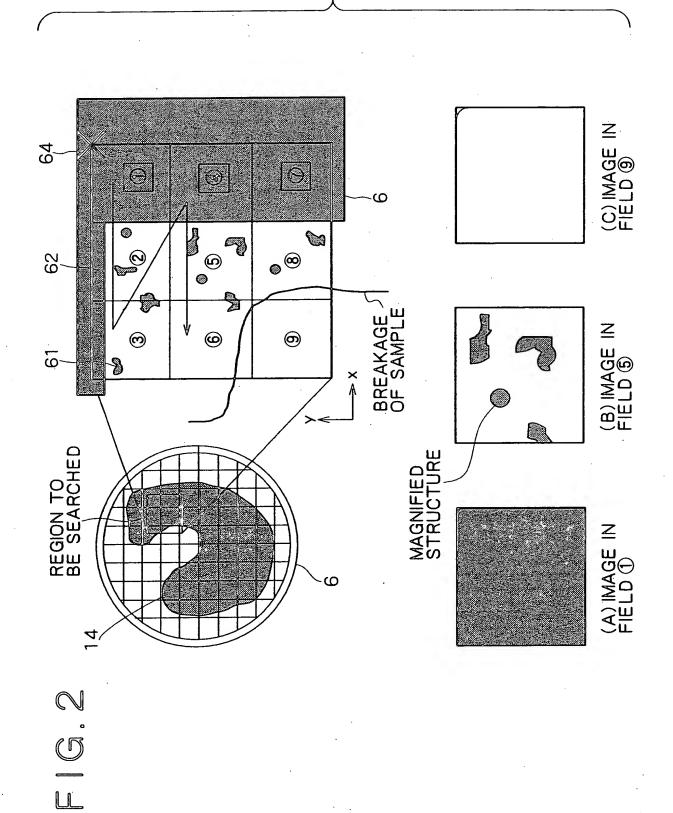
FIG.1





F1G.3B Σ 65 61 F1G.3A Σ Z

Z

FIG.4

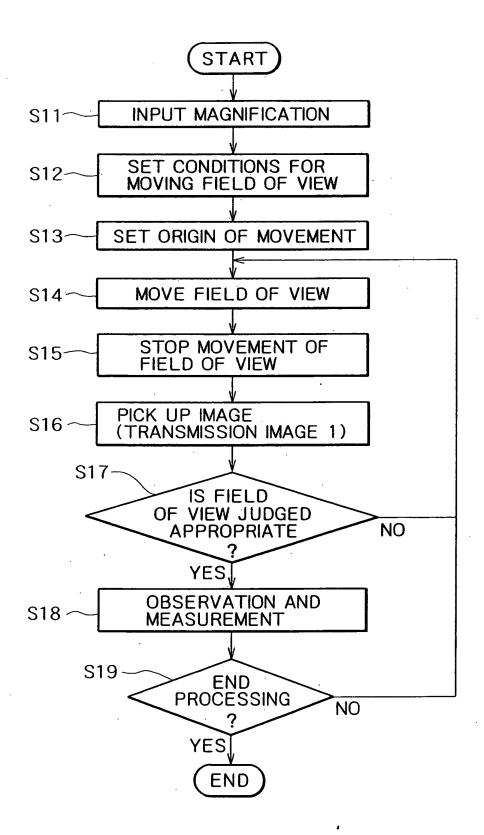
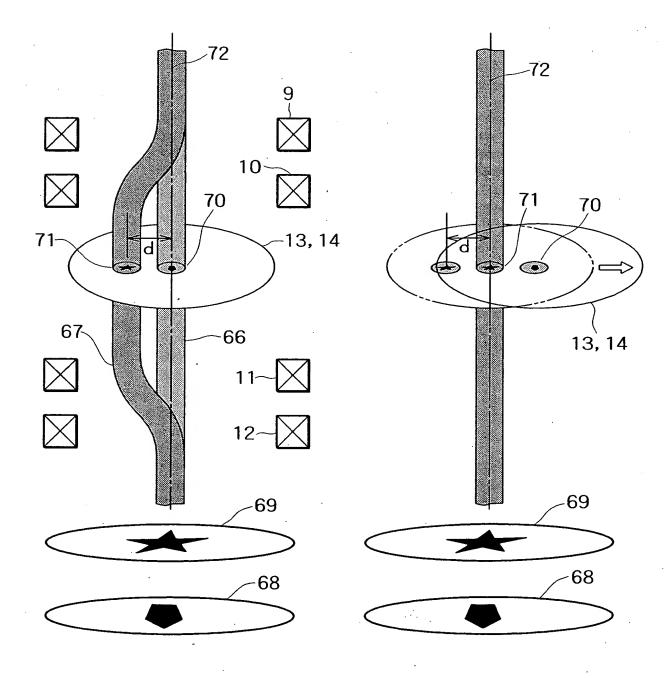


FIG.5A

FIG.5B



ELECTROMAGNETIC MOVEMENT OF FIELD OF VIEW USING ELECTRON BEAM DEFLECTING COIL

MECHANICAL MOVEMENT OF FIELD OF VIEW USING SAMPLE STAGE DRIVER

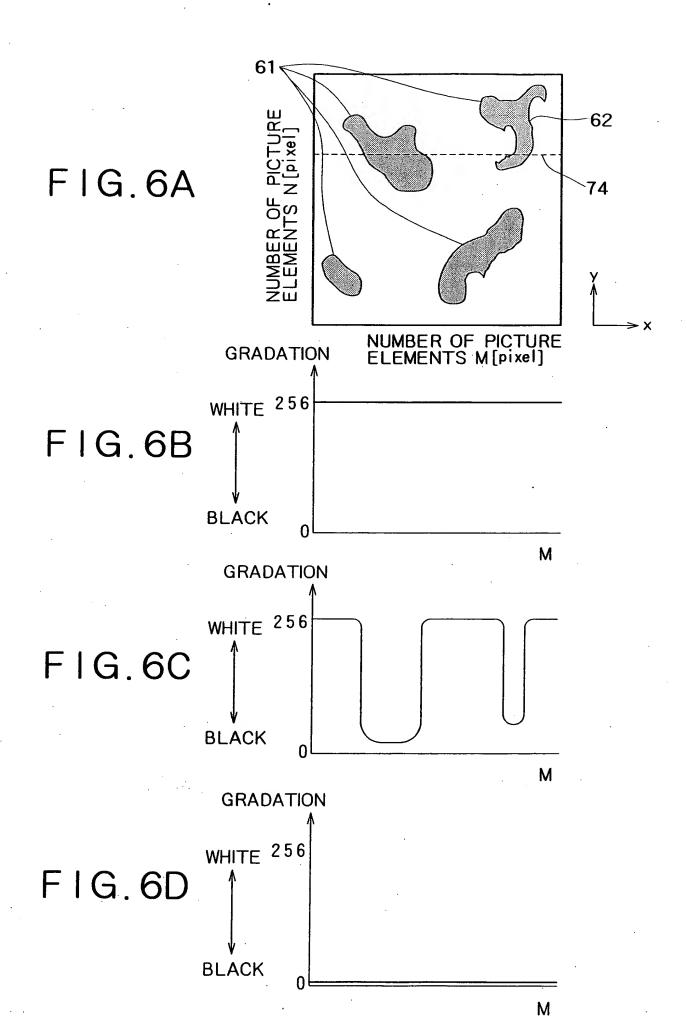
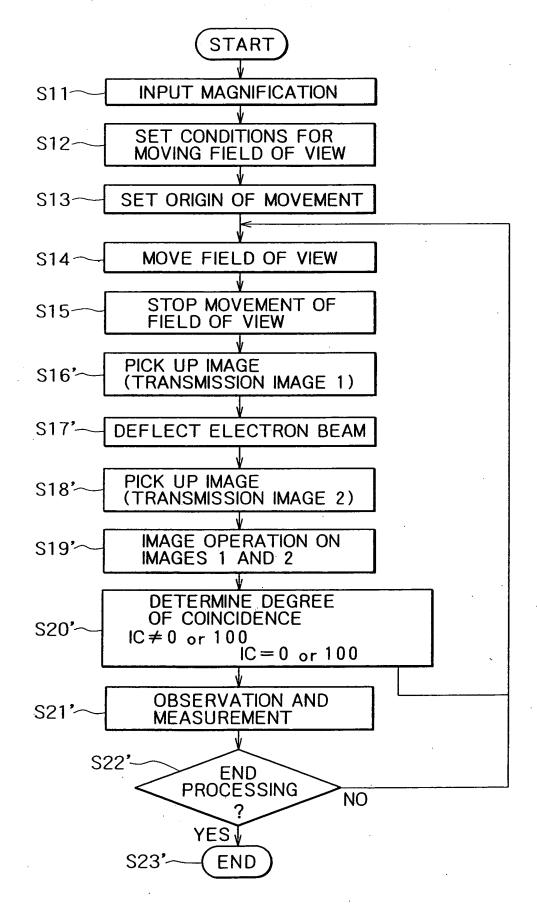


FIG.7



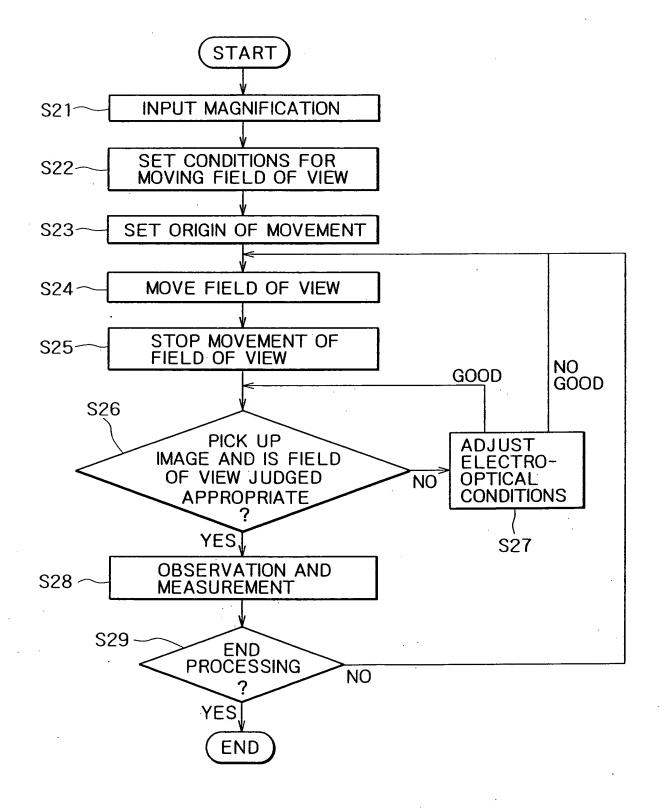


FIG.9

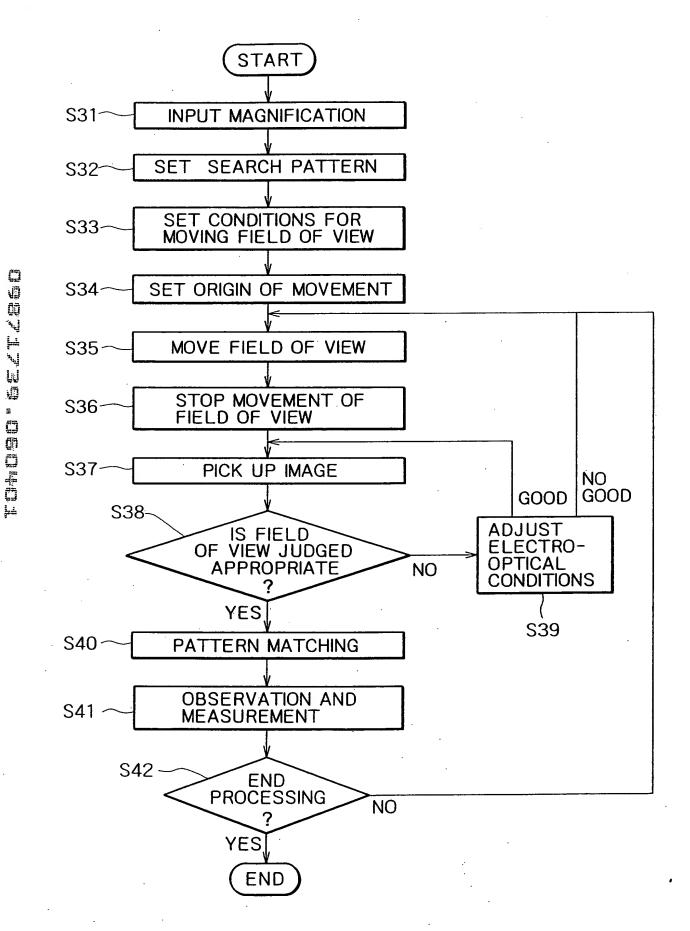
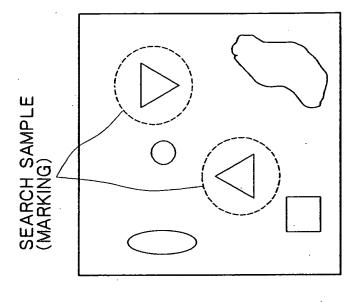


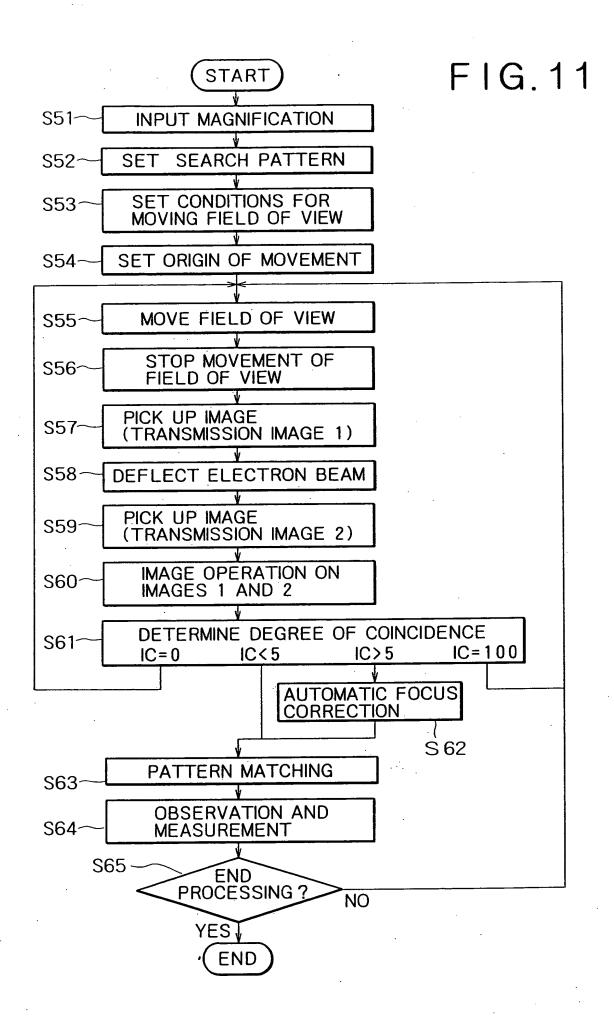
FIG. 10A

FIG. 10B



PICKED-UP FIELD OF VIEW NUMBER OF SEARCH SAMPLES=2

SEARCH TARGET PATTERN



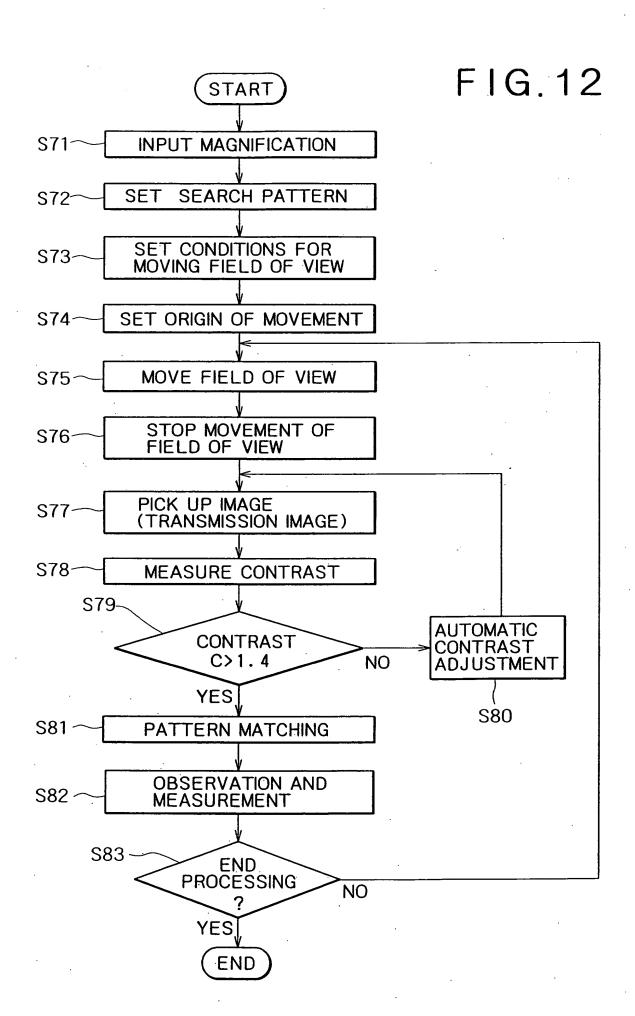
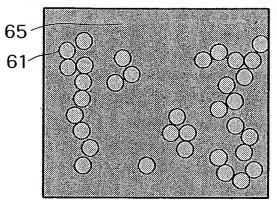
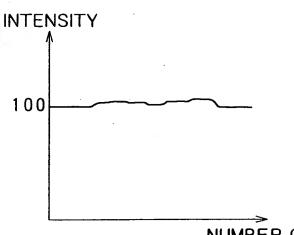


FIG. 13 (1)

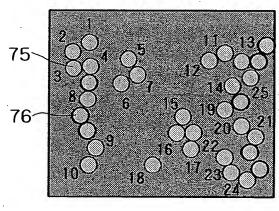


CONTRAST C=1.1



NUMBER OF PIXELS

FIG. 13 (2)



CONTRAST C=1.2

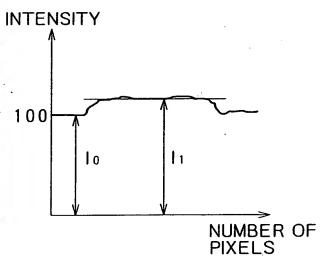
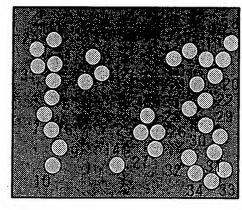
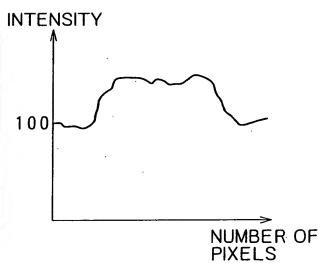


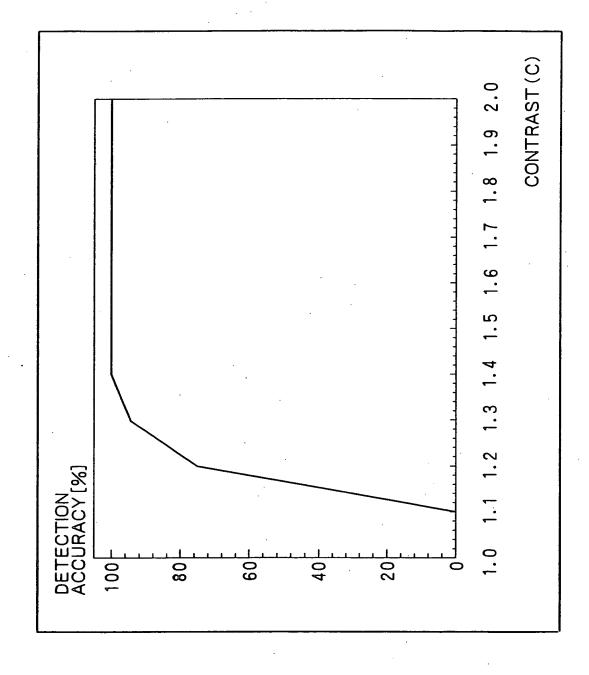
FIG. 13 (3)



CONTRAST C=1.6



F | G | 14



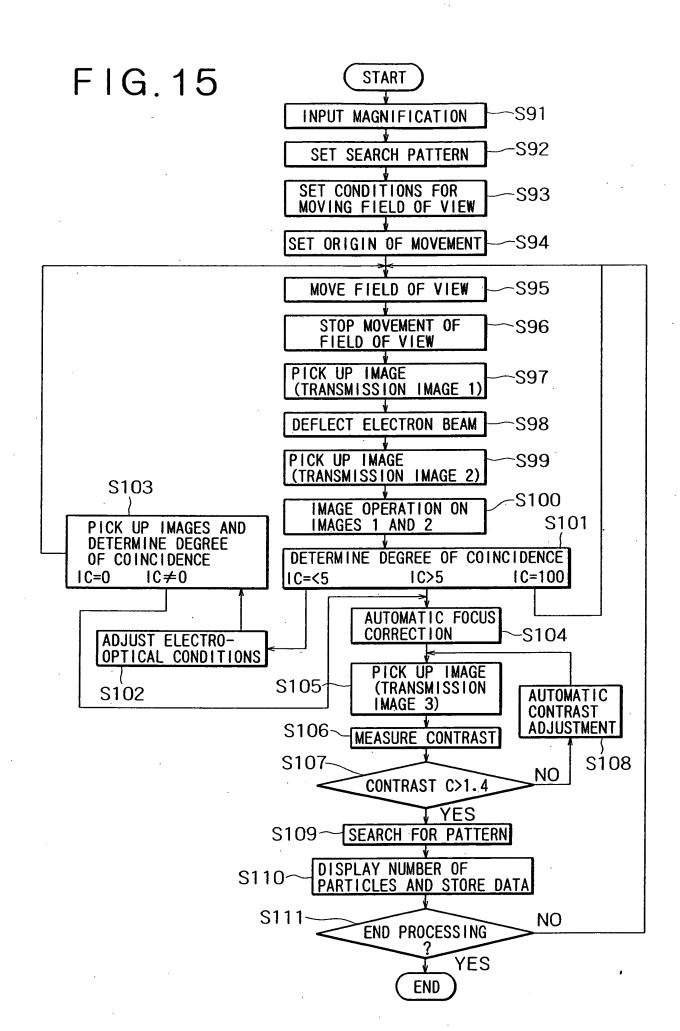


FIG. 16

